

Abstract Submitted
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Electron-induced secondary electrons in low-pressure capacitively coupled radio-frequency plasmas¹ BENEDEK HORVATH, Wigner Research Centre for Physics, JULIAN SCHULZE, Ruhr-University Bochum, West Virginia University, KATHARINA NOESGES, SEBASTIAN WILCZEK, Ruhr-University Bochum, ZOLTAN DONKO, Wigner Research Centre for Physics, ARANKA DERZSI, West Virginia University, Wigner Research Centre for Physics — We investigate the effects of secondary electrons (SEs) induced by electrons on the discharge characteristics in low-pressure single-frequency capacitively coupled plasmas (CCPs) by Particle-in-Cell/Monte Carlo Collisions simulations. Such SEs (δ -electrons) were found to have a remarkable influence on the plasma parameters in argon at 0.5 Pa and 6.7 cm gap between SiO₂ electrodes (B. Horváth et al. 2017 *Plasma Sources Sci. Technol.* **26** 124001). Here we study the impact of δ -electrons on the ionization dynamics and plasma parameters at various pressures and voltage amplitudes, assuming different SE yields for ions (γ -coefficient). The voltage amplitude, the gas pressure and the value of the γ -coefficient affect the role of δ -electrons in the ionization dynamics. While their effect is most striking at low pressures, high voltage amplitudes and high γ -coefficients, in the whole parameter regime investigated here the realistic description of the electron-surface interaction changes significantly the computed plasma parameters compared to results based on a widely used simple model for the description of the electron-surface interaction.

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